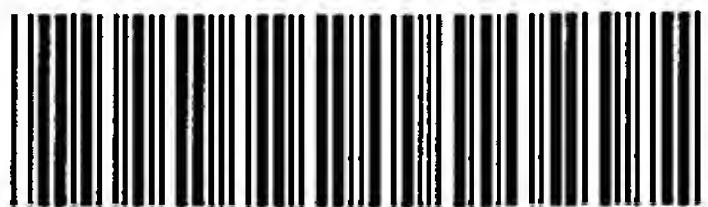


**Search Notes****Application/Control No.**

10/709,425

**Examiner**

Mohamed Charioui

**Applicant(s)/Patent under Reexamination**

WANG ET AL.

**Art Unit**

2857

**SEARCHED**

Class	Subclass	Date	Examiner
702	57-59, 64, 69, 117, 118, 119	12/1/2005	MC
702	120-123	12/1/2005	MC
702	183, 184	12/1/2005	MC
702	193	12/1/2005	MC
714	738,744	12/1/2005	MC
324	76.11	12/1/2005	MC
324	158.1	12/1/2005	MC
324	765	12/1/2005	MC

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East: (latch\$up near test\$3)".ti" and "pin" and program\$6	12/1/2005	MC
East: (latch\$up near test\$3)".ti" and "pin" and program\$6	12/1/2005	MC
East: (test\$6 near chip) with current with ground	12/1/2005	MC
East: (test\$6 near pin) with current with measur\$6	12/1/2005	MC
East: "PMU" with pin with current	12/1/2005	MC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner